

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/687,749 | Applicant(s)/Patent Under Reexamination FEE ET AL. | |
| | Examiner Filip Zec | Art Unit 3744 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-6,464,312 | 10-2002 | Tenhundfeld et al. | 312/405 |
| | B | US-5,199,273 | 04-1993 | Silva et al. | 62/298 |
| | C | US-5,551,250 | 09-1996 | Yingst et al. | 62/234 |
| | D | US-3,805,545 | 04-1974 | Buchser et al. | 62/443 |
| | E | US-4,870,735 | 10-1989 | Jahr et al. | 29/890.035 |
| | F | US-5,732,565 | 03-1998 | Ramakrishnan et al. | 62/298 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.